SICRIT[®] – the Ion Source for direct MS measurements



Upgrade your MS into a sensitive VOC sensor for fast screening or 24/7 monitoring



Simplifying mass spectrometry

Direct MS has shown its potential for fast screening analysis and for real-time VOC monitoring.

Plasmion's SICRIT[®] Ion Source enables to perform sensitive direct MS measurements on any LC-MS instrument without sample preparation. It allows for continuous VOC monitoring as well as direct quantitative headspace or liquid analysis in the low-ppt-level.

The smart plug & play design ensures a fast installation and an easy operation.

Instantaneous results without sample preparation for targeted or non-targeted screening of VOC emissions.



Enabling a unique range of applications

Headspace HRMS analysis of PFCAs in coating powder formulation.



Parallel online-monitoring of 500+ aroma compounds during coffee roasting.







#Explosives



#PFCA



#Coffee



More information on our website

Want to see more details and additional applications? Visit **www.plasmion.com**

A solution based on superior technology (SICRIT®)

Increased sensitivity



The locally confined ionization in a small capillary in extension of the MS-inlet avoids the loss of ions by coulombic repulsion and increases sensitivity.

No sample preparation



The ambient character of the ionization source allows to analyze solid, liquid, or gaseous samples in room air without sample preparation (direct screening).

Direct MS screening & automated clustering of honey samples





B | Bio Forest Honey





No fragmentation



The unique shape of the cold plasma enables a soft ionization of analytes and allows for identification based on exact mass.

High-resolution spectrum of SICRIT[®]

High reproducibility



Enhanced range of analytes



Three simultaneous ionization mechanisms expand the range of detectable analytes, covering polar and non-polar components.



Delivering significant economical advantages

Plasmion's Ion Source leads to a significant reduction in analysis time



The plug & play mechanism of the SICRIT[®] Ion Source enables an installation within less than a minute. It does neither require calibration nor sample preparation and is thus suitable to answer analytical questions fast and efficiently.

Plasmion's Ion Source reduces costs and capital expenditure

The SICRIT[®] Ion Source leads to a significant decrease in running costs for chemical analyses, as it does not require any consumables like noble gases. Since it can be used for almost all MS-related applications, it avoids the capital expenditure for multiple dedicated ion sources.

Plasmion's Ion Source meets highest demands in terms of performance



The flexibility of the SICRIT[®] Ion Source in coupling with any LC-MS instrumentation gives unlimited access to the detector's performance needed for the analytical task. The flow-through design of the source additionally increases the analyte transfer into the respective LC-MS system, enhancing sensitivity.



Provided by trusted partners

Shimadzu and Plasmion provide an integrated solution based on the plug & play SICRIT[®] ionization technology. All instrumentation (MS. Autosampler, SICRIT[®]) can be directly ordered via Shimadzu. If you already have an MS. the SICRIT[®] setup can also be ordered directly from Plasmion.



tion source and the connection modules

and mechanical connection to the MS head-space quantification and automation

pling and avoidance of condensation

Shimadzu products

SHIMADZU AOC-6000 autosampler

The AOC-6000 is developed to maximize productivity in the laboratory. The system switches between sample introduction methods automatically, enabling continuous operation combining different sample introduction methods.

In combination with Plasmion's product portfolio, highly automated sampling and sample analysis can be realized. Furthermore, workflows with and without GCcan be implemented by one instrumental setup.



Plasmion products

Ion Source

The SICRIT[®] Ion Source can be operated with any carrier gas (even room air) and thus enables direct MS screening. Moreover, it enables a gas-tight measurement of sensitive processes or fully quantitative connection to classical GC/LC methods.

The cold plasma ionization based on a dielectric barrier discharge enables fragment-free measurement of multiple analytes.





SC-30 control unit

The SICRIT[®] SC-30 Control Unit enables to control the cold plasma in the SICRIT[®] Ionization Source as well as the required parameters of all connection modules (GC-SPME/LC/IR desorption). All parameters can also be controlled via a respective software. An integration with software of other vendors is not required to operate the system.

Plasmion products





MS interfaces

The SICRIT[®] MS interfaces are dedicated for specific MS instruments to establish an electronic and mechanical connection. There are interfaces available for all common MS instruments of Shimadzu. Interfaces to other instruments are available upon request.

GC/SPME module

The SICRIT[®] GC/SPME Module combines ionization technology with state-of-the-art sample separation and/or enrichment techniques.

- It enables a direct SICRIT[®]-MS connection from a GC or microbalance via a heated transfer line.
- It enables direct SPME-SICRIT[®]-MS measurements with automated injections featuring an AOC-6000 or PAL autosampler.
- It enables fully quantitative direct measurements (manual or automated) of liquids and headspace samples.





Direct sampling line

Our sampling line extends the ion source inlet and allows for loss-free transfer of analytes from closed chambers like fermenters, roasters, etc. The sampling line consists of a 40 cm inert stainless-steel tube which can be heated up to 200°C. The line is mounted to Plasmion's MS interfaces.



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